Likelihood Methods: A Companion to the NEPPSR analysis project

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Outline

- We have arranged a "hands-on" mini-course on fitting techniques using the ROOT framework
- To fit data, we often use the MINUIT package from CERN, which is a fitting engine for numerically minimizing
- It is built-in to ROOT, or can be called stand-alone
- Instead of using it as a black box, we thought we'd show how conceptually simple its operation really is
- Quick review of some basics of probabilities
- Maximum Likelihood basics
- Properties of the ML method, using specific examples

and YES, there will be a test (Especially for repeat NEPPSR offenders)

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Probability Basics

- Suppose X is a random variable. The probability of throwing X between x, x+dx is P(x)dx
 - P(x) is called the *probability density function (pdf)* for X

$$\int P(x)dx = 1$$

- The *Expectation value* of a function f(x) over P(x) is: $E(f) = \int f(x)P(x)dx$
- The most common expectations we use are the first few moments of the pdf:

$$E(1) = \int 1P(x)dx = 1$$
 normalization

$$E(x) = \int xP(x)dx = \overline{x}$$
 mean

$$E((x - \overline{x})^2) = \int (x - \overline{x})^2 P(x)dx = \sigma^2$$
 variance

• See Craig Blocker's talk for a more detailed introduction NEPPSR, 2006 Colin Gay, Yale University

Probability Basics

- The Conditional Probability P(x|a) is the pdf for X, given that a is true
- For example, P(x|d) = probability that our detector measures a particle passing a wire at distance x, given that the particle is truly at distance d
- Or: P(m|m₀) = probability of measuring mass m given the true mass is m₀
- We use pdfs all the time in our Monte Carlos: we know true value of masses, trajectories, etc, and turn into finite samples of quantities reconstructed by our detector via these pdfs
- Our job with real data is the inverse: Given a finite sample of measurements of a quantity, to infer our pdf and true value for the quantity

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Samples

- Let X have pdf P(x). A Sample of size N is a set of {x_i} of N throws of X.
- When we plot, e.g., the mass of all of our reconstructed top quarks, we are visualizing our sample pulled from the pdf P(m|m₀), where m₀ is the true top mass
- Our job is, based on our finite sample, to estimate the true value m_0 , and to quantify how certain our estimation is
- For this, we need an *estimator* for m₀
- Some estimators are better than others
 - e.g. My estimator is "150 GeV", no matter what
 - This is an estimator, but not a very good one!

- What properties would we like in our estimators?
- Consistent: As our sample size N increases, we'd like our estimator to converge to the true value. Such an estimator is called *consistent*.
- Efficient: There is a theoretical minimum for the variance of an estimator about the true value, given a sample of size N (called the Minimum Variance Bound)
 - An estimator with variance equal to the MVB is *efficient*
- Unbiased: An estimator whose expectation value (mean) is equal to the true value is called *unbiased*

Maximum Likelihood Estimators

- Suppose we have a sample of N measurements of a variable m, and we know the pdf for m is P(m|m₀).
 - However, we don't know m₀ in fact, it is the physics quantity we are interested in measuring

lihood
$$L(m_0) = \prod_{i=1}^N P(m_i \mid m_0)$$

- The Maximum Likelihood Estimator (MLE) m^* for m_0 is the value of m_0 that maximizes the joint likelihood
- MLEs are not always unbiased, but are consistent and efficient. They are also asymptotically normal.
- Extracting the MLE for a quantity is called "fitting" the data

Form the *like*

Least-squares fit (review?)

- First fit most of us learn is a least-squares or χ^2 fit
- Put data into histogram bins: centers x_i , value y_i with uncertainty σ_i
- Choose function $f(x_i | \vec{\theta})$ which predicts the bin contents y_i as a function of the "fit parameters" $\vec{\theta}$

• Form
$$\chi^2 = \sum \frac{(f(x_i | \vec{\theta}) - y_i)^2}{\sigma_i^2}$$

• The Least-Squares Principle states that the best estimate for the parameters $\vec{\theta}$ are the ones which minimize χ^2

Binned vs Unbinned fits

- The LSQ fit is an example of a binned fit
- A LSQ fit has the nice property that in addition to supplying the fit parameters, it also tells us how "good" the fit function approximates the data
- Binned fits with few (or zero) events per bin are problematic
- Gaussian approx of uncertainty σ_i on bin contents is 0
 - Contribution to χ^2 undefined
 - Root just ignores these bins => fit biased high
- Likelihood fits give us the ability to deal with data in an unbinned way
 - Ideal for small statistics, or sparse data

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MLE Properties – NEPPSR project

- I'll develop the concepts of the ML fit using an analytically solvable case
- You will write a fitting program, fit to data supplied by Stephane, Kevin and John, and can compare to analytic result
- I'll use a common real-world case fitting for the lifetime of a data sample of decay times

Lifetime Likelihood

We can write the probability density function for an exponential decay in two ways:

$$P(t \mid \tau) = \frac{1}{\tau} e^{-t/\tau}$$
 or $P(t \mid \Gamma) = \Gamma e^{-\Gamma t}$

 These are properly normalized (more on this later)

$$\int P(t \mid \tau) dt = 1$$

• Construct the likelihood

$$L(\tau) = \prod_{i=1}^{N} P(t_i \mid \tau)$$

from the N time measurements $\{t_i\}, i = 1, N$

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Lifetime Likelihood

- Rather than Maximizing the likelihood, we usually take the log
- Numerically, the likelihood can get extremely small, resulting in precision issues. log is better.
- log is monotonic, so maximizing logL is equivalent to L
- Our main fitting package, MINUIT, finds Minima, so we multiply by -1 and Minimize:

$$-\log L(\tau) = -\sum_{i=1}^{N} \log P(t_i \mid \tau)$$
$$= -\sum_{i=1}^{N} \log(\frac{1}{\tau}e^{-t_i/\tau})$$
$$= \sum_{i=1}^{N} (\log \tau + \frac{t_i}{\tau})$$
$$= N\log \tau + \frac{1}{\tau} \sum_{i=1}^{N} t_i$$

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Maximizing the Likelihood

• To find the minimum, we set the first derivative to 0

$$\frac{\partial (-\log L)}{\partial \tau} = \mathbf{0} = \frac{N}{\tau} - \frac{1}{\tau^2} \sum_{i=1}^{N} t_i$$

$$\implies N\tau = \sum_{i=1}^{N} t_i$$

$$\implies \tau^* = \frac{1}{N} \sum_{i=1}^{N} t_i \quad (= E(t) = \overline{t} = \text{mean})$$

 au^{*} is the ML estimator for the true lifetime au

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Likelihood for a Lifetime



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Numerical method

 While we can solve this system analytically, in general we must build up the likelihood numerically by looping over the events and adding up the –log P:

```
sum = 0;
for (i=0; i<N; i++) {
   sum += log(tau) + t[i]/tau;
}
```

Find minimum sum by scanning in tau

 This allows for very complicated probability functions to be handled in a straightforward way

What about the width?

 What if we considered the width to be our unknown, rather than the lifetime?

$$-\log L(\Gamma) = -\sum_{i=1}^{N} \log(\Gamma e^{-\Gamma t_i}) = \sum_{i=1}^{N} (-\log \Gamma + \Gamma t_i)$$
$$= -N \log \Gamma + \Gamma \sum_{i=1}^{N} t_i$$



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• Let's calculate the expectation (mean) value of our

estimator
$$\tau^* = \frac{1}{N} \sum_{i=1}^N t_i$$
 given the true lifetime is τ

$$E(\tau^*) = E(\frac{1}{N} \sum_{i=1}^N t_i) = \frac{1}{N} \sum_{i=1}^N E(t_i)$$

$$= \frac{1}{N} \sum_{i=1}^N \int t_i \frac{1}{\tau} e^{-t_i/\tau} dt_i$$

$$= \int_0^\infty t \frac{1}{\tau} e^{-t/\tau} dt = t e^{-t/\tau} \Big|_0^\infty - \int_0^\infty e^{-t/\tau} dt$$

$$= \tau$$

• The mean value of our fit result for τ^* , if we repeat the experiment many times, is the true value τ =>Unbiased

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Bias (continued)

• What about Γ ?

$$E(\Gamma^*) = E(\frac{N}{\sum_{i=1}^{N} t_i}) = N \int ... \int \frac{1}{\sum_{i=1}^{N} t_i} P(t_1 \mid \Gamma) ... P(t_N \mid \Gamma) dt_1 ... dt_N \neq \Gamma$$

- Hence Γ^* is a biased estimator. This sounds bad ...
- However, fitting for lifetime or width gives the same answer: Remember

$$\Gamma^* = \mathbf{1} / \tau^*$$

• You can get a fine fit with either. It should be no surprise that $E(\frac{1}{x}) \neq \frac{1}{E(x)}$

so that if estimator x is unbiased, 1/x must be biased NEPPSR, 2006 Colin Gay, Yale University

MLE transformation invariance

- In fact, the result of the likelihood fit is invariant under parameter transformation:
 - If f(x) is any function of the estimator x, then the MLE for f(x) satisfies

 $(f(x))^* = f(x^*)$

- That is, fitting for x, and then applying the transformation f gives the same result as fitting for f(x)
- Thus there's more than one way to skin any cat ...

Uncertainty on ML Estimator

• Taylor expand likelihood about minimum:

$$\log L(\theta) = \log L|_{\theta^*} + \frac{1}{2} \frac{\partial^2 \log L}{\partial \theta^2} \bigg|_{\theta = \theta^*} (\theta - \theta^*)^2$$

$$L(\theta) = L|_{\theta^*} e^{\frac{1}{2} \frac{\partial^2 \log L}{\partial \theta^2}\Big|_{\theta = \theta^*} (\theta - \theta^*)^2}$$

• **If we consider this a probability density for the true value of the parameter θ , we see it is a Gaussian, with mean θ^* and variance

$$\sigma^{2} = V(\theta) = -\frac{1}{\frac{\partial^{2} \log L}{\partial \theta^{2}}}\Big|_{\theta = \theta^{*}}$$

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Meaning of Likelihood

- Depends on if you are Bayesian or Frequentist
 - While most particle physicists are professed frequentists, they also seem to me to be closet Bayesians at times
- Let's be a bit more careful in notation. The likelihood is

$$L(\{t_i\} \mid \tau) = \prod_{i=1}^N P(t_i \mid \tau)$$

- Bayes: We'd like to invert the probability, and consider this as the probability density for the true value τ given the observations t_i
- In general $P(A|B) \neq P(B|A)$. In fact, Bayes' thm is:

$$P(A \mid B) = \frac{P(B \mid A)P(A)}{P(B)}$$

(follows from P(A | B)P(B) = P(B | A)P(A))

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Meaning of Likelihood

• Thus
$$P(\tau \mid data) = \frac{P(data \mid \tau)P(\tau)}{P(data)}$$

- **P**(*data*) is some constant normalization
- If we take the so-called *prior probability* function *P*(τ) to be flat, then the likelihood *is* the probability distribution for the true value of τ

 $P(\tau \mid data) = P(data \mid \tau) = L(\tau)$

- Writing in a more suggestive way: $\log L(\theta) = \log L|_{\theta^*} - \frac{1}{2} \frac{(\theta - \theta^*)^2}{\sigma^2}$
- Hence the values of the likelihood for the true value of θ being 1, 2, n σ from the central value are

$$-\log L(\theta^* \pm 1\sigma) = -\log L|_{\theta^*} + \frac{1}{2}$$
$$-\log L(\theta^* \pm 2\sigma) = -\log L|_{\theta^*} + 2$$
$$-\log L(\theta^* \pm n\sigma) = -\log L|_{\theta^*} + \frac{1}{2}n^2$$

- For fits, $\chi^2 = \sum \frac{(f_i x_i)^2}{\sigma_i^2}$, $\Delta \chi^2 = 1, 4, 9$ correspond to 1, 2, 3 σ excursions
- Same for ML fits, except factor of 1/2

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Likelihood Uncertainty



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Estimated Variance of Lifetime fit

In our case of the lifetime fit:

$$-\log L = N\log \tau + \frac{1}{\tau}\sum_{i=1}^{N} t_{i}$$

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Lifetime fit Uncertainties

- Note that samples with fitted lifetimes that fluctuate low ALSO have the smallest uncertainty!
- This can easily (and did/does) cause world-averages of many measurements to be biased low, as low values get the largest weight
- More correct to combine the likelihood curves to average many experiments
- This is now done behind the scenes for many measurements
 - Experts supply sampling of the likelihood curve for their fit
 - L curves are ADDED
 - Minimum of summed L found, and Δ L=1/2 gives combined uncertainty

Goodness of Fit

- Consider the two data sets below, made into histograms for visualization. Both result in the same ML estimator for the lifetime.
- Surely, data set 1 is "more" likely than data set 2, right?
- Surely, since it is more exponential, the value of the likelihood function for the 1st should be larger than for the 2nd, right? Each events "probability" should be higher, resulting in a net larger likelihood.



Goodness of Fit

• Unfortunately, this is wrong. Recall:

$$-\log L = N\log \tau + \frac{1}{\tau}\sum_{i=1}^{N} t_i \quad \text{and} \quad \tau^* = \frac{1}{N}\sum_{i=1}^{N} t_i$$

$$-\log L_{\min} = N\log \tau^* + \frac{1}{\tau^*} \sum_{i=1}^N t_i = N\log(\frac{1}{N} \sum t_i) + \frac{N}{\sum t_i} \sum t_i$$
$$= N(-\log N + 1 + \log \sum t_i) = N(\log \tau^* + 1)$$

• ANY sample with the same $\sum t_i$ produces the SAME estimate $\tau^* = \sum t_i / N$ with the SAME value for the -logL of $N(\log \tau^* + 1)$

- The two previous fits are "equally likely"!
- This is a weakness of the ML method it doesn't naturally supply a "goodness of fit" metric

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Moral

- The ML method will not save you from yourself!
- Sanity check of results essential!
- How likely is likely needs care: e.g. from a self-help mathematics website:

<u>Definition of Unlikely Event</u>

- The event that may not happen is an unlikely event.
- In other words, unlikely event is an event that is not likely to happen.

Likelihood Normalization

- You must be vigilant that your likelihood is properly normalized (or at least its normalization doesn't change)
- Easiest way is to normalize each building-block probability distribution
- Ignoring this can cause real problems:
 - Consider a ML fit with 10,000 data events
 - Suppose the normalization of the underlying pdfs changes from 1 to 0.9999

$$-\log L = \sum_{i=1}^{N} \log P(t_i | \tau)$$

$$\Rightarrow \sum_{i=1}^{10,000} \log 0.9999P(t_i | \tau)$$

$$= \sum_{i=1}^{10,000} (\log 0.9999 + \log P(t_i | \tau))$$

$$= \sum_{i=1}^{10,000} (-.0001 + \log P(t_i | \tau))$$

$$= \sum_{i=1}^{10,000} \log P(t_i | \tau) - 1$$

$$More than 1 sigma Change! Colin Gay, Yale University$$

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ML Fit with Constraint

- It is easy to add external constraints on fit parameters
- Let's assume Gaussian uncertainty on constraint
 - e.g. add in the world-average knowledge as given by PDG

$$L = P(\tau \mid \tau_{PDG}, \sigma_{PDG}) \prod_{i=1}^{N} P(t_i \mid \tau)$$

$$-\log L = -\log P(\tau \mid \tau_{PDG}, \sigma_{PDG}) + \sum_{i=1}^{N} \log P(t_i \mid \tau)$$

$$= -\log(\frac{1}{\sqrt{2\pi}\sigma_{PDG}} e^{-\frac{(\tau - \tau_{PDG})^2}{2\sigma_{PDG}^2}}) + \sum_{i=1}^{N} \log P(t_i \mid \tau)$$

$$= \sum_{i=1}^{N} \log P(t_i \mid \tau) + \frac{(\tau - \tau_{PDG})^2}{2\sigma_{PDG}^2} + \log \sqrt{2\pi}\sigma_{PDG}$$

$$Original \quad \frac{1}{2}\chi^2 \text{ penalty} \quad \text{Constant}$$

$$Wandering by$$

$$1 \text{ sigma from constraint costs 1/2 unit of likelihood (=1 \text{ sigma})}$$

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Lifetime with imperfect Detector

- All detectors have non-zero time resolution
 - -> Let's add this effect in to our fit
- Assume detector has a gaussian resolution function, with mean = 0 (i.e. unbiased) and width

$$P(t \mid \tau) = Exp(t', \tau) \otimes G(0, \sigma)$$
$$= \frac{1}{\sqrt{2\pi\sigma\tau}} \int_0^\infty e^{-t'/\tau} e^{-\frac{(t-t')^2}{2\sigma^2}} dt'$$

• Consider the exponentials. The exponent is:

$$-\frac{t}{\tau} - \frac{(t-t')^2}{2\sigma^2} = -\frac{1}{2\sigma^2} (t'^2 - 2t't + t^2 + 2\frac{\sigma^2}{\tau}t')$$
$$= -\frac{1}{2\sigma^2} (t'^2 - 2t'(t - \frac{\sigma^2}{\tau}) + t^2)$$
$$= -\frac{1}{2\sigma^2} \left[(t' - (t - \frac{\sigma^2}{\tau}))^2 + 2\frac{\sigma^2 t}{\tau} + \frac{\sigma^4}{\tau^2} \right]$$
$$= -\frac{1}{2\sigma^2} (t' - (t - \frac{\sigma^2}{\tau}))^2 - \frac{t}{\tau} - \frac{\sigma^2}{2\tau^2}$$

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Lifetime with Imperfections

PDF becomes $P(t \mid \tau) = \frac{1}{\sqrt{2\pi}\sigma\tau} \int_0^\infty e^{-t/\tau} e^{-\frac{\sigma^2}{2\tau^2}} e^{-\frac{(t'-(t-\frac{\sigma^2}{\tau}))^2}{2\sigma^2}} dt'$ $=\frac{1}{\tau}e^{-t/\tau}e^{-\frac{\sigma^{2}}{2\tau^{2}}}\frac{1}{\sqrt{2\pi}\sigma}\int_{0}^{\infty}e^{-\frac{(t'-(t-\frac{\sigma^{2}}{\tau}))^{2}}{2\sigma^{2}}}dt'$ $=\frac{1}{\tau}e^{-t/\tau}e^{-\frac{\sigma^{2}}{2\tau^{2}}}\frac{1}{\sqrt{2\pi\sigma}}\int_{-(t-\frac{\sigma^{2}}{2})}^{\infty}e^{-\frac{t'^{2}}{2\sigma^{2}}}dt'$ $=\frac{1}{\tau}e^{-t/\tau}e^{-\frac{\sigma^{2}}{2\tau^{2}}}\frac{1}{\sqrt{\pi}}\int_{-\frac{1}{\sqrt{2}}(\frac{t}{\sigma}-\frac{\sigma}{\tau})}^{\infty}e^{-x^{2}}dx$ $=\frac{1}{\tau}e^{-t/\tau}e^{-\frac{\sigma^2}{2\tau^2}}\frac{1}{2}erfc(-\frac{1}{\sqrt{2}}(\frac{t}{\sigma}-\frac{\sigma}{\tau}))$

Effect of Worsening Resolution

$$P(t \mid \tau) = \frac{1}{\tau} e^{-t/\tau} e^{-\frac{\sigma^2}{2\tau^2}} \frac{1}{2} \operatorname{erfc}(-\frac{1}{\sqrt{2}}(\frac{t}{\sigma} - \frac{\sigma}{\tau}))$$

• As σ grows, pdf looks less like exponential, more like the gaussian resolution function







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Lifetime with Cutoff

- Suppose we are measuring the ½ life of some radioactive material, but we only have T days to run our experiment
- Our probability density for observing a decay must cut off at T days, affecting the normalization

$$P(t \mid \tau) = \frac{1}{1 - e^{-T/\tau}} \frac{1}{\tau} e^{-t/\tau}$$

$$-\log L(\tau) = -\sum_{i=1}^{N} \log(\frac{1}{1 - e^{-T/\tau}} \frac{1}{\tau} e^{-t_i/\tau})$$
$$= -N(\log(1 - e^{-T/\tau}) + \log \tau) - \frac{1}{\tau} \sum_{i=1}^{N} t_i$$

- Now solve numerically ... Note that the normalization changes with $\boldsymbol{\tau}$

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Lifetime with Background

- Suppose we have a prompt (0 lifetime) background in our sample (measured with resolution $\,\sigma$)
- We can easily handle this by making our per-event probability:

$$P(t \mid \tau, f) = f \frac{1}{\tau} e^{-t/\tau} \otimes G(0, \sigma) + (1 - f)G(t \mid 0, \sigma)$$

f = fraction of signal G = gaussian

• Form –log L as usual, minimize wrt both au, f

Multiple variables

- Maximum Likelihood fit easily handles multiple fit variables

 simply multiply in the probability densities for each new variable
- Least-squares fit has problems with such fits
 - As we add more and more dimensions to our fit, binned methods encounter trouble
 - Data gets spread thin over large number of histogram bins, resulting in few entries (or zero) per bin => problematic for the fit
- e.g. Adding the reconstructed mass to the decay time as variables to fit and distinguish signal from background

Summary

- Maximum Likelihood fit is a powerful, convenient technique for estimating parameters from finite samples
- Unbinned, so small statistics, sparse data ok
- Best choice for many-parameter fits
- For large N, gives unbiased value, converges to true value, and has minimum uncertainty possible
- Constant normalization critical
- Auxiliary goodness of fit required
- Visualization can be difficult
- Most serious fits you do in your career will be Maximum Likelihood fits
- Stephane will talk about the hands-on part of the project

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